

<b>Notice of References Cited</b>	Application/Control No. 10/523,761		Applicant(s)/Patent Under Reexamination SHERMAN, BERNARD CHARLES	
	Examiner Jeffrey T. Palenik		Art Unit 1615	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,228,398	05-2001	Devane et al.	424/484
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Website showing mesh-metric conversions: <a href="http://www.sigmaaldrich.com/Area_of_Interest_JResearch_Essentials/Chemicals/Key_Resources/Technical_Library/Particle_Size_Conversion.html">http://www.sigmaaldrich.com/Area_of_Interest_JResearch_Essentials/Chemicals/Key_Resources/Technical_Library/Particle_Size_Conversion.html</a>
	V	
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